

**Search Notes**

Application/Control No.

10/060,301

Examiner

Young J. Kim

Applicant(s)/Patent under  
Reexamination

NAKAMURA ET AL.

Art Unit

1637

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)  see enclosed for text-search strategy	1/9/2008	YJK